

SN74F2244

25-Ω OCTAL BUFFER/DRIVER WITH 3-STATE OUTPUTS

SDFS095B – NOVEMBER 1993 – REVISED JANUARY 1996

- 3-State Outputs Drive Bus Lines or Buffer-Memory Address Registers
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (N) 300-mil DIPs

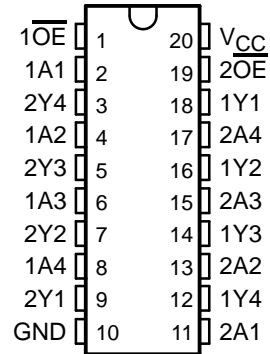
description

This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 25-Ω resistors in the lower output circuit reduce ringing and eliminate the need for external resistors.

The SN74F2244 is characterized for operation from 0°C to 70°C.

DW OR N PACKAGE
(TOP VIEW)



FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT
$\overline{\text{OE}}$	A	Y
L	H	H
L	L	L
H	X	Z



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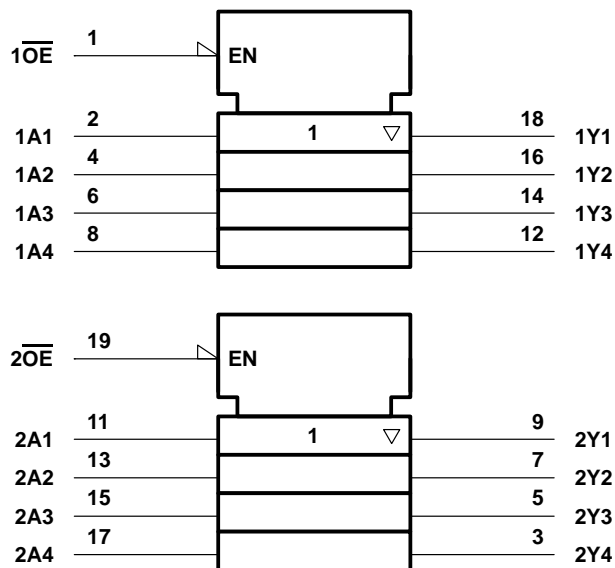
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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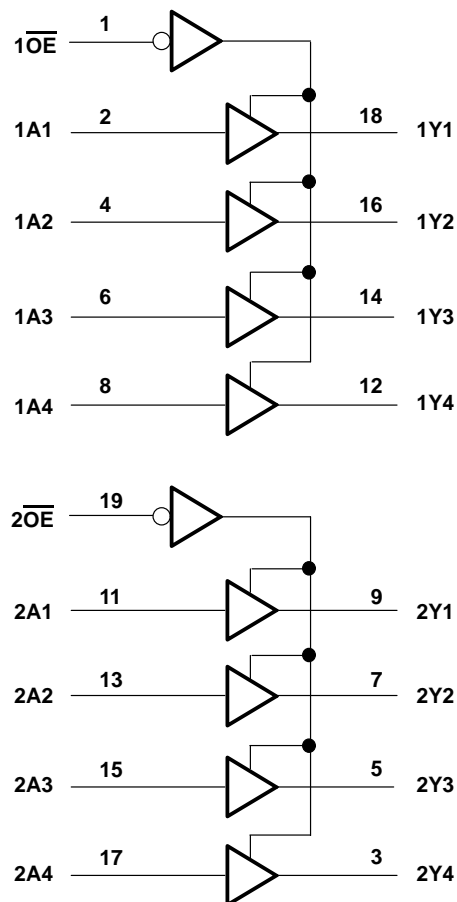
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–1.2 V to 7 V
Input current range, I_I	–30 mA to 5 mA
Voltage range applied to any output in the disabled or power-off state, V_O	–0.5 V to 5.5 V
Voltage range applied to any output in the high state, V_O	–0.5 V to V_{CC}
Current into any output in the low state, I_O	30 mA
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded if the input current ratings are observed.

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WITH 3-STATE OUTPUTS

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recommended operating conditions

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			– 18	mA
I _{OH}	High-level output current			– 15	mA
I _{OL}	Low-level output current			12	mA
T _A	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITION†	MIN	TYP†	MAX	UNIT
V _{IK}	V _{CC} = 4.5 V, I _I = – 18 mA			– 1.2	V
V _{OH}	V _{CC} = 4.5 V, I _{OH} = – 3 mA	2.4	2.8		V
	V _{CC} = 4.5 V, I _{OH} = – 15 mA	2	2.3		
	V _{CC} = 4.75 V, I _{OH} = – 3 mA	2.7			
V _{OL}	V _{CC} = 4.5 V, I _{OL} = 1 mA	0.2	0.5		V
	V _{CC} = 4.5 V, I _{OL} = 12 mA	0.5	0.75		
I _I	V _{CC} = 5.5 V, V _I = 0.5 V			0.1	mA
I _{OZH}	V _{CC} = 5.5 V, V _O = 7 V			50	μA
I _{OZL}	V _{CC} = 5.5 V, V _O = 2.7 V			– 50	μA
I _{IH}	V _{CC} = 5.5 V, V _I = 2.7 V			20	μA
I _{IL}	Any $\overline{\text{OE}}$ input			– 1	mA
	Any A input			– 1.6	
I _{OS} ‡	V _{CC} = 5.5 V, V _O = 0	– 100		– 225	mA
I _{CC}	V _{CC} = 5.5 V, Outputs open	Outputs high		40	mA
		Outputs low		60	
		Outputs disabled		60	

† All typical values are at V_{CC} = 5 V, T_A = 25°C.

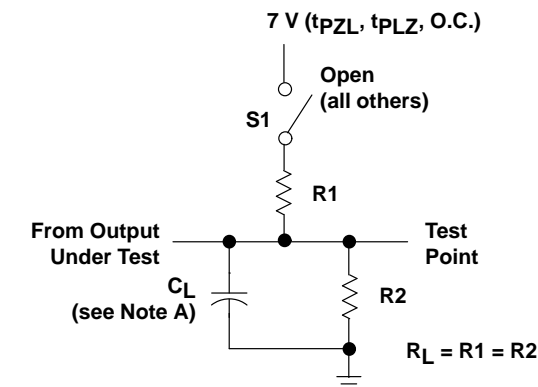
‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

switching characteristics (see Figure 1)

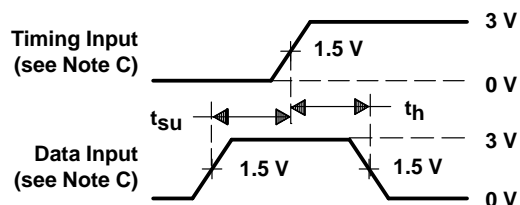
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, C _L = 50 PF, R ₁ = 500 Ω, R ₂ = 500 Ω, T _A = 25°C		V _{CC} = 4.5 V TO 5.5 V, C _L = 50 PF, R ₁ = 500 Ω, R ₂ = 500 Ω, T _A = MIN TO MAX§		UNIT
			MIN	MAX	MIN	MAX	
t _{PLH}	A	Y	1.5	7	1.5	7	ns
t _{PHL}			2.5	8	2	8	
t _{PZH}	$\overline{\text{OE}}$	Y	1.5	9	1	9.5	ns
t _{PZL}			2.5	11.5	2.5	12	
t _{PHZ}	$\overline{\text{OE}}$	Y	1.5	9	1	9.5	ns
t _{PLZ}			1.5	8.5	1.5	9.5	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

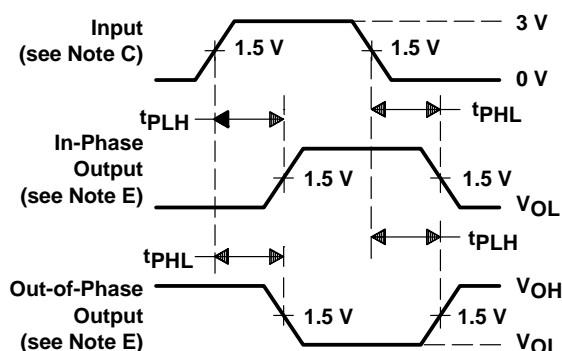
PARAMETER MEASUREMENT INFORMATION



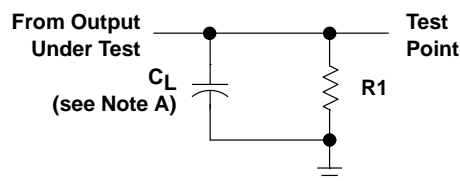
LOAD CIRCUIT FOR 3-STATE AND OPEN-COLLECTOR OUTPUTS



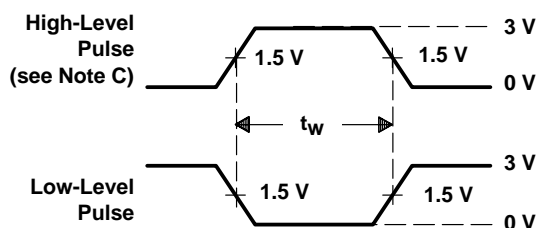
VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



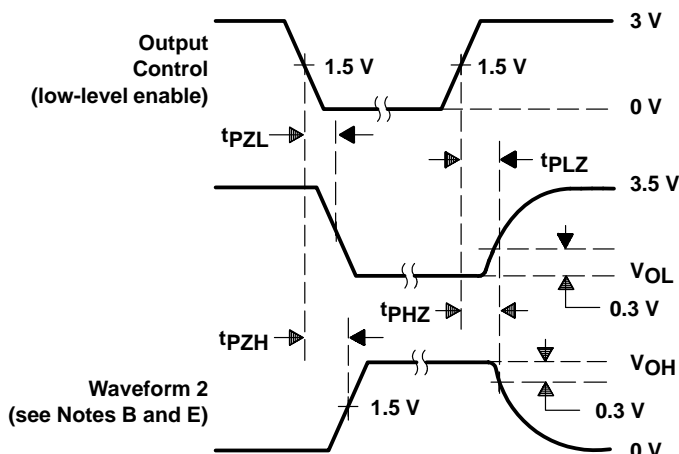
VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES (see Note D)



LOAD CIRCUIT FOR TOTEM-POLE OUTPUTS



VOLTAGE WAVEFORMS PULSE DURATION



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f \leq 2.5$ ns, duty cycle = 50%.
D. When measuring propagation delay times of 3-state outputs, switch S1 is open.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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